

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/693,076	WEI ET AL.	
Examiner	Art Unit	
Michael La Villa	1775	

	SEAR	CHED	
Class	Subclass	Date	Examiner
428	627, 634, 34.1, 156, 220, 332	3/16/2006	ML
	408, 409		
	457, 698		
	586, 215		
	336, 446		
	450, 469		
428	641	3/16/2006	ML .

INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	D/	ATE	EXMR		
WEST SEARCH	3/16	6/2006	ML		
Inventor Search	3/16	5/2006	ML		
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